

Source	Background yield variation	Signal yield variation
Electron identification and isolation	2.0–3.2%	1.9–2.9%
Jet b tagging (heavy-flavour jets)	2.5%	2.5–2.7%
Integrated luminosity	2.5%	2.5%
Trigger efficiency	0.5–1.4%	0.4–1.4%
Pileup	0.3–1.4%	0.3–1.5%
Muon identification	0.4–0.8%	0.4–0.7%
PDFs	0.6–0.7%	1.0–1.4%
Jet b tagging (light-flavour jets)	0.3%	0.3–0.4%
Muon isolation	0.2–0.3%	0.1–0.2%
Jet energy scale	<0.1–0.3%	0.7–1.0%
Jet energy resolution	0.1%	<0.1%
Affecting only $t\bar{t}$ (85.1–95.7% of the total bkg.)		
μ_R and μ_F scales		12.8–12.9%
$t\bar{t}$ cross section		5.2%
Simulated sample size		<0.1%
Affecting only DY in $e^\pm\mu^\mp$ channel (0.9% of the total bkg.)		
μ_R and μ_F scales		24.6–24.7%
Simulated sample size		7.7–11.6%
DY cross section		4.9%
Affecting only DY estimate from data in same-flavour events (7.1–10.7% of the total bkg.)		
Simulated sample size		18.8–19.0%
Normalisation		5.0%
Affecting only single top quark (2.5–2.9% of the total bkg.)		
Single t cross section		7.0%
Simulated sample size		<0.1–1.0%
μ_R and μ_F scales		<0.1–0.2%
Affecting only signal		
	SM signal	$m_\chi = 400$ GeV
μ_R and μ_F scales	24.2%	4.6–4.7%
Simulated sample size	<0.1%	<0.1%